

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/544,787	ROCA I CABARROCAS ET AL.	
		Examiner	Art Unit	Page 1 of 1
		DANIEL WHALEN	2829	

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,403,756 A	04-1995	Yoshinouchi et al.	438/162
*	B	US-6,078,059 A	06-2000	Nakata, Yukihiko	257/57
	C	US-			
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	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Roca et al., "Stable microcrystalline silicon thin-film transistors produced by the layer-by-layer technique", Journal of Applied Physics, 1999 American Institute of Physics, pages 7079-7082
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.